

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/549,251
Applicant : Yuichiro Sasaki et al.
Filed : September 13, 2005
Title : "BEAM CURRENT MEASURING APPARATUS AND BEAM
CURRENT MEASURING METHOD USING THE SAME"

Confirmation No. : TBD
TC/A.U. : TBD
Examiner : TBD

Customer No. : 052054
Docket No. : 38771

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

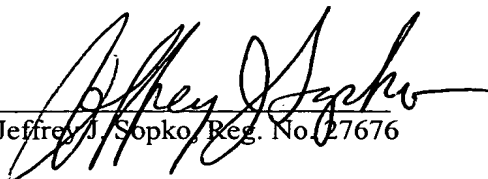
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P.O. Box 1450
Alexandria, Va. 22131-1450

Sir/Madam:

In accordance with 37 C.F.R. § 1.98, applicant is submitting herewith Form PTO-1449 listing references for consideration by the Examiner. Also submitted herewith is a legible copy of each reference listed.

If there are any fees resulting from this communication, please charge said fees to our Deposit Account No. 16-0820, Order No. 38771.

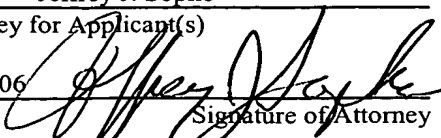
Respectfully submitted,
PEARNE & GORDON LLP

By: 
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February 20, 2006

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22131-1450 on the date indicated below.

Jeffrey J. Sopko
Name of Attorney for Applicant(s)
February 20, 2006
Date

Signature of Attorney

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 38771	SERIAL NO. 10/549,251
SUPPLEMENTAL INFORMATION DISCLOSURE CITATION BY APPLICANT <i>(USE SEVERAL SHEETS IF NECESSARY)</i>		APPLICANT: Yuichiro Sasaki et al.	
		FILING DATE: September 13, 2005	GROUP ART UNIT: TBD

U.S. PATENT DOCUMENTS							
Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date If Appropriate
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

FOREIGN PATENT DOCUMENTS							
		Document No.	Date	Country	Class	Subclass	Translation
	L						
	M						
	N						
	P						
	Q						

OTHER REFERENCES <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>		
R		Tanabe, "A Cryogenic Current-Measuring Device with Nano-Ampere Resolution at the Storage Ring TARN II", 09/1998, Pages 455-464
S		Hao et al., "HTS Flux Concentrator For Non-Invasive Sensing Of Charges Particle Beams", 06/2001, Pages 469-470
T		

Examiner:	Date Considered
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***Examiner:** Initial if reference considered, regardless of whether citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.